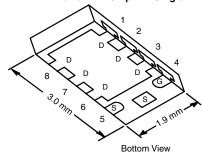
Vishay Siliconix

# P-Channel 20 V (D-S) MOSFET

PRODU	PRODUCT SUMMARY					
V <sub>DS</sub> (V)	R <sub>DS(on)</sub> (Ω) (Max.)	I <sub>D</sub> (A) <sup>a</sup>	Q <sub>g</sub> (Typ.)			
	0.0096 at V <sub>GS</sub> = - 4.5 V	- 25				
- 20	0.0132 at V <sub>GS</sub> = - 2.5 V	- 25	43 nC			
	0.0220 at V <sub>GS</sub> = - 1.8 V	- 7				

#### **PowerPAK ChipFET Single**



#### Ordering Information:

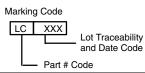
Si5415AEDU-T1-GE3 (Lead (Pb)-free and Halogen-free)

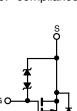
#### **FEATURES**

- TrenchFET® Power MOSFET
- Thermally Enhanced PowerPAK® ChipFET Package
  - Small Footprint Area
  - Low On-Resistance
- 100 % R<sub>q</sub> and UIS Tested
- Typical ESD Protection: 5500 V (HBM)
- Material categorization: For definitions of compliance please see <a href="https://www.vishay.com/doc?99912"><u>www.vishay.com/doc?99912</u></a>

#### **APPLICATIONS**

- Portable Devices such as Smart Phones, Tablet PCs and Mobile Computing
  - Battery Switch
  - Load Switch
  - Power Management





COMPLIANT

HALOGEN

**FREE** 

P-Channel MOSFET

Parameter		Symbol	Limit	Unit	
Drain-Source Voltage		V <sub>DS</sub>	- 20	V	
Gate-Source Voltage		V <sub>GS</sub>	± 8		
	T <sub>C</sub> = 25 °C		- 25 <sup>a</sup>		
Continuous Dunin Comment /T. 150 °C\	T <sub>C</sub> = 70 °C		- 25 <sup>a</sup>		
Continuous Drain Current (T <sub>J</sub> = 150 °C)	T <sub>A</sub> = 25 °C	I <sub>D</sub>	- 15 <sup>b, c</sup>		
	T <sub>A</sub> = 70 °C		- 12 <sup>b, c</sup>		
Pulsed Drain Current (t = 100 μs)	·	I <sub>DM</sub>	- 70	A	
Continuous Courses Dunis Diada Coursest	T <sub>C</sub> = 25 °C		- 25 <sup>a</sup>		
Continuous Source-Drain Diode Current	T <sub>A</sub> = 25 °C	I <sub>S</sub>	- 2.6 <sup>b, c</sup>		
Single Avalanche Current		I <sub>AS</sub>	- 15		
Single Avalanche Energy	L = 0.1 mH	E <sub>AS</sub>	11	mJ	
	T <sub>C</sub> = 25 °C		31		
Manian and David Dispiration	T <sub>C</sub> = 70 °C	D	20	١٨/	
Maximum Power Dissipation	T <sub>A</sub> = 25 °C	P <sub>D</sub>	3.1 <sup>b, c</sup>	w	
	T <sub>A</sub> = 70 °C		2 <sup>b, c</sup>		
Operating Junction and Storage Temperature Range		T <sub>J</sub> , T <sub>stg</sub>	- 50 to 150	00	
Soldering Recommendations (Peak Temperatur	_	260	°C		

THERMAL RESISTANCE RATINGS					
Parameter		Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient <sup>b, f</sup>	t ≤ 5 s	R <sub>thJA</sub>	34	40	°C/W
Maximum Junction-to-Case (Drain)	Steady State	R <sub>thJC</sub>	3	4	C/VV

#### Notes

- a. Package limited.
- b. Surface mounted on 1" x 1" FR4 board.
- c. t = 5 s
- d. See solder profile (<u>www.vishay.com/doc?73257</u>). The PowerPAK ChipFET is a leadless package. The end of the lead terminal is exposed copper (not plated) as a result of the singulation process in manufacturing. A solder fillet at the exposed copper tip cannot be guaranteed and is not required to ensure adequate bottom side solder interconnection.
- e. Rework conditions: manual soldering with a soldering iron is not recommended for leadless components.
- f. Maximum under steady state conditions is 90 °C/W.



# Vishay Siliconix

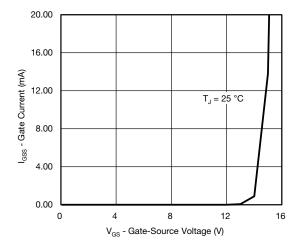
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static	-					
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	- 20			V
V <sub>DS</sub> Temperature Coefficient	$\Delta V_{DS}/T_{J}$			- 11		
V <sub>GS(th)</sub> Temperature Coefficient	$\Delta V_{GS(th)}/T_J$	I <sub>D</sub> = - 250 μA		2.8		mV/°C
Gate-Source Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS} = V_{GS}, I_D = -250 \mu\text{A}$	- 0.4		- 1	V
		$V_{DS} = 0 \text{ V}, V_{GS} = \pm 8 \text{ V}$			± 2	
Gate-Source Leakage	$I_{GSS}$	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 4.5 \text{ V}$			± 0.2	
		V <sub>DS</sub> = - 20 V, V <sub>GS</sub> = 0 V			- 1	μΑ
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> = - 20 V, V <sub>GS</sub> = 0 V, T <sub>J</sub> = 55 °C			- 10	
On-State Drain Currenta	I <sub>D(on)</sub>	$V_{DS} \le -5 \text{ V}, V_{GS} = -4.5 \text{ V}$	- 10			Α
	= (=,	V <sub>GS</sub> = - 4.5 V, I <sub>D</sub> = - 10 A		0.0081	0.0096	
Drain-Source On-State Resistance <sup>a</sup>	R <sub>DS(on)</sub>			0.0110	0.0132	Ω
	20(0.1)	V <sub>GS</sub> = - 1.8 V, I <sub>D</sub> = - 2 A		0.0170	0.0220	
Forward Transconductance <sup>a</sup>	9 <sub>fs</sub>	V <sub>GS</sub> = - 10 V, I <sub>D</sub> = - 10 A		47		S
Dynamic <sup>b</sup>				l		
Input Capacitance	C <sub>iss</sub>			4300		pF
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> = - 10 V, V <sub>GS</sub> = 0 V, f = 1 MHz		445		
Reverse Transfer Capacitance	C <sub>rss</sub>			400		
Total Gate Charge	Q <sub>g</sub>	V <sub>DS</sub> = - 10 V, V <sub>GS</sub> = - 8 V, I <sub>D</sub> = - 14 A		80	120	nC
				43	65	
Gate-Source Charge		V <sub>DS</sub> = - 10 V, V <sub>GS</sub> = - 4.5 V, I <sub>D</sub> = - 14 A		7		
Gate-Drain Charge	$Q_{qd}$			11.4		
Gate Resistance	R <sub>q</sub>	f = 1 MHz	0.6	3.3	6.6	Ω
Turn-On Delay Time	t <sub>d(on)</sub>			30	60	
Rise Time	t <sub>r</sub>	$V_{DD}$ = - 10 V, $R_L$ = 1 $\Omega$		45	90	
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong -10 \text{ A}, V_{GEN} = -4.5 \text{ V}, R_g = 1 \Omega$		75	150	
Fall Time	t <sub>f</sub>			25	50	
Turn-On Delay Time	t <sub>d(on)</sub>			12	25	ns
Rise Time	$t_r$ $V_{DD} = -10 \text{ V}, R_L = 1 \Omega$			5	10	1
Turn-Off Delay Time	t <sub>d(off)</sub>	$I_D \cong$ - 10 A, $V_{GEN} =$ - 8 V, $R_g =$ 1 $\Omega$		80	160	
Fall Time	t <sub>f</sub>			20	40	
Drain-Source Body Diode Characteristi	cs					
Continuous Source-Drain Diode Current	Is	T <sub>C</sub> = 25 °C			- 25	
Pulse Diode Forward Current (t = 100 μs)	I <sub>SM</sub>				- 70	Α
Body Diode Voltage	$V_{SD}$	I <sub>S</sub> = - 10 A, V <sub>GS</sub> = 0 V		- 0.8	- 1.2	V
Body Diode Reverse Recovery Time	t <sub>rr</sub>			35	70	ns
Body Diode Reverse Recovery Charge	Q <sub>rr</sub>	10 A dl/dt 100 A/: T 05 00		21	40	nC
Reverse Recovery Fall Time	I <sub>E</sub> = - 10 A, dl/dt = 100 A/µs, I <sub>1</sub> = 25 °C			20		
						ns

#### Notes

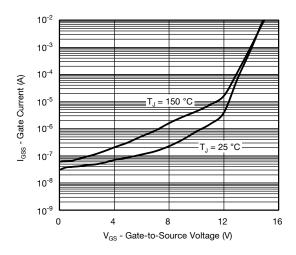
- a. Pulse test; pulse width  $\leq 300~\mu s,$  duty cycle  $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

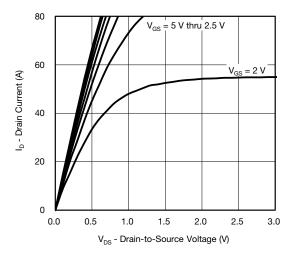




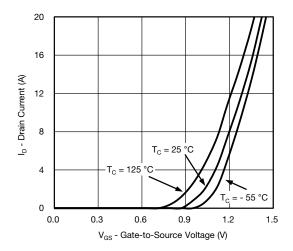
#### Gate Current vs. Gate-Source Voltage



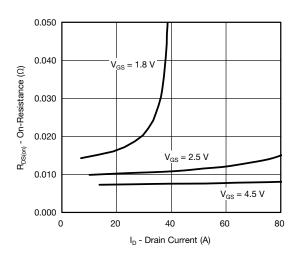
Gate Current vs. Gate-Source Voltage



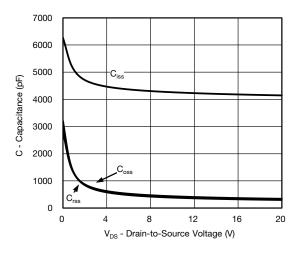
**Output Characteristics** 



**Transfer Characteristics** 

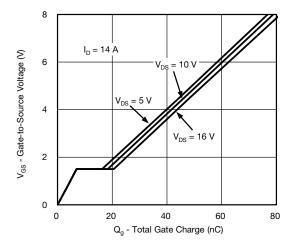


On-Resistance vs. Drain Current and Gate Voltage

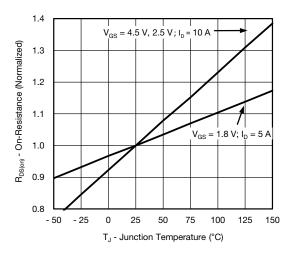


Capacitance

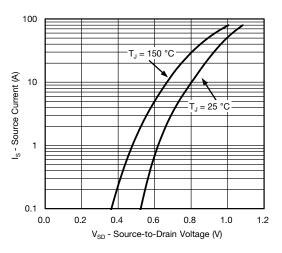




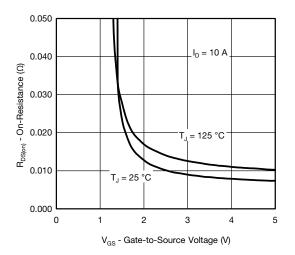
#### **Gate Charge**



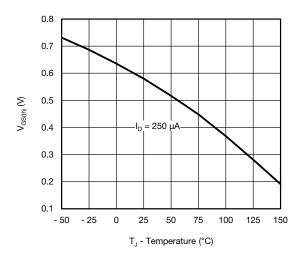
On-Resistance vs. Junction Temperature



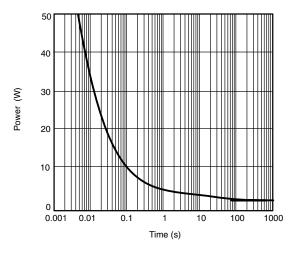
Soure-Drain Diode Forward Voltage



On-Resistance vs. Gate-to-Source Voltage

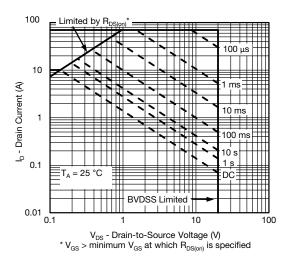


**Threshold Voltage** 

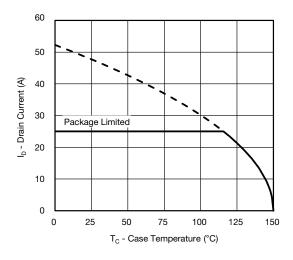


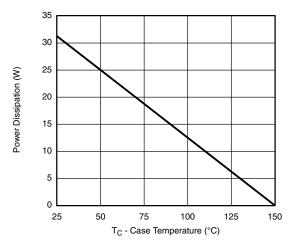
Single Pulse Power, Junction-to-Ambient





Safe Operating Area, Junction-to-Ambient



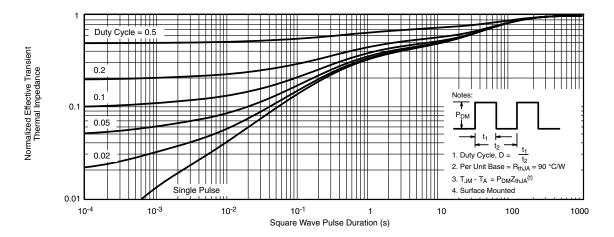


**Current Derating\*** 

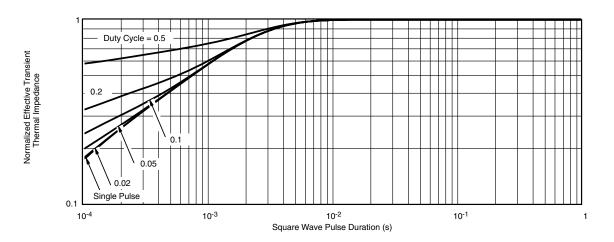
**Power Derating** 

<sup>\*</sup> The power dissipation  $P_D$  is based on  $T_{J(max.)} = 150$  °C, using junction-to-case thermal resistance, and is more useful in settling the upper dissipation limit for cases where additional heatsinking is used. It is used to determine the current rating, when this rating falls below the package limit.





#### Normalized Thermal Transient Impedance, Junction-to-Ambient

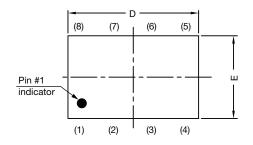


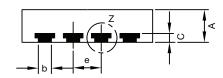
Normalized Thermal Transient Impedance, Junction-to-Case

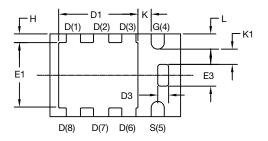
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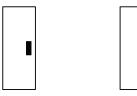
# PowerPAK® ChipFET® Case Outline







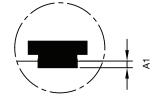
Backside view of single pad



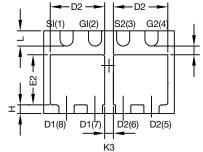
Side view of single



Side view of dual



Detail Z



Backside view of dual pad

DIM.	MILLIMETERS			INCHES			
	MIN.	NOM.	MAX.	MIN.	NOM.	MAX.	
Α	0.70	0.75	0.85	0.028	0.030	0.033	
A1	0	-	0.05	0	-	0.002	
b	0.25	0.30	0.35	0.010	0.012	0.014	
С	0.15	0.20	0.25	0.006	0.008	0.010	
D	2.92	3.00	3.08	0.115	0.118	0.121	
D1	1.75	1.87	2.00	0.069	0.074	0.079	
D2	1.07	1.20	1.32	0.042	0.047	0.052	
D3	0.20	0.25	0.30	0.008	0.010	0.012	
E	1.82	1.90	1.98	0.072	0.075	0.078	
E1	1.38	1.50	1.63	0.054	0.059	0.064	
E2	0.92	1.05	1.17	0.036	0.041	0.046	
E3	0.45	0.50	0.55	0.018	0.020	0.022	
е		0.65 BSC		0.026 BSC			
Н	0.15	0.20	0.25	0.006	0.008	0.010	
K	0.25	-	-	0.010	-	ı	
K1	0.30	-	-	0.012	-	ı	
K2	0.20	-	-	0.008	-	ı	
K3	0.20	-	-	0.008	-	ı	
L	0.30	0.35	0.40	0.012	0.014	0.016	

#### C14-0630-Rev. E, 21-Jul-14

#### Note

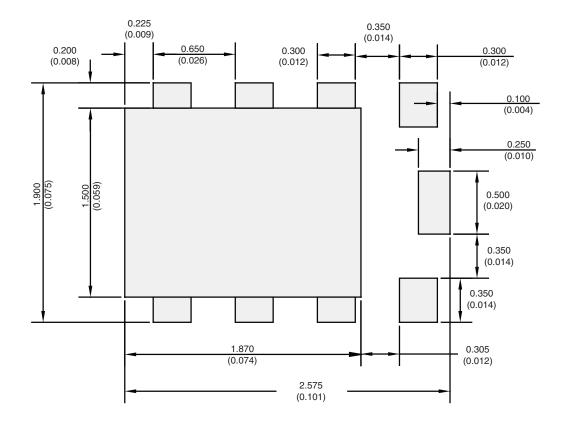
DWG: 5940

Revision: 21-Jul-14

• Millimeters will govern



## RECOMMENDED MINIMUM PADS FOR PowerPAK® ChipFET® Single



Recommended Minimum Pads Dimensions in mm/(Inches)

Return to Index

APPLICATION NOTE



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Revision: 13-Jun-16 1 Document Number: 91000